MEMC 00-1400(2806.1) PATENT

Art Unit 176

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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of Robert J. Falster et al. Serial No. 10/039,196 Filed January 2, 2002 Confirmation No. 7221

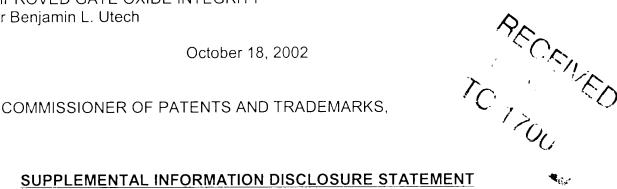
PROCESS FOR PREPARING SINGLE CRYSTAL SILICON H IMPROVED GATE OXIDE INTEGRITY

Examiner Benjamin L. Utech

October 18, 2002

TO THE COMMISSIONER OF PATENTS AND TRADEMARKS,

SIR:



In accordance with 37 C.F.R. 1.97 and 1.98 and MPEP 609, and in compliance with the duty of disclosure set forth in 37 C.F.R. 1.56, applicants submit copies of the references listed on the attached PTO/SB/08A for consideration by the Patent and Trademark Office in the above-entitled application and to be made of record therein.

This Information Disclosure Statement is being submitted pursuant to 37 C.F.R. 1.97(b) in that Applicant believes that it is being filed before the mailing date of the first Office action on the merits. Accordingly, neither a statement nor fee under 37 C.F.R. 1.97(c) is required. If Applicant is mistaken, and the mailing date of the first Office action on the merits precedes the filing of this Information Disclosure Statement, Applicant authorizes the Commissioner to charge the fee due under 37 C.F.R. 1.17(p) to Deposit Account No. 19-1345.

Respectfully submitted,

Edward J. Heilek, Reg. No. 31,525 SENNIGER, POWERS, LEAVITT & ROEDEL One Metropolitan Square, 16th Floor St. Louis, Missouri 63102 (314) 231-5400

PTO/SB/08A	Complete if Known		
INFORMATION DISCLOSURE	Application Number	10/039,196	
STATEMENT BY APPLICANT	Filing Date	January 2, 2002.	
(use as many sheets as necessary)	Confirmation Number	7221	
	First Named Inventor	Robert J. Falster	
	Group Art Unit	1765	
	Examiner Name	Benjamin L. Utech	
Sheet 1 of 1	Attorney Docket No.	MEMC 00-1400(2806.1)	

			U	.S. PATEN	T DOCUMENTS		
	Cite No.1	U.S. Patent Document					
Examiner Initials*			Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	
	15	5,502,0	)10		Nadahara et al.	03-26-1996	
		Foreign Patent Document				Date of Publication of	
		F			ENT DOCUMENTS		
Examiner Initials*	Cite No.'	Office Number¹ Kind Code² (if known)		Code <sup>2</sup> (if	Name of Patentee or Applicant of Cited Document	Cited Document MM-DD-YYYY	T'
	16	wo	98/45507	A1	MEMC Electronic Materials, Inc.	10-15-1998	
	17	wo	00/00675	A1	MEMC Electronic Materials, Inc.	01-06-2000	
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Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.					
	18	Partial	International Sea	rch for analogoi	us PCT application Serial No. PCT/US	602/01127 dated	1

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ļ	Examiner	Date	
1	Signature	Considered	

<sup>\*</sup>EXAMINER initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered not use copy of this form with next communication to applicant.

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